Search Notes	
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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/015,613	BAUDISCH, PATRICK	
Examiner	Art Unit	
Aaron M. Richer	2676	

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Class	Subclass	Date	Examiner
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INI	ERFERENC	E SEARCH	ED
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST (US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB) - See Search History Printout	3/1/2006	AMR
345/1.3 (text search only)	3/1/2006	AMR
Updated	11/19/2006	AMR
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